Abstracts

40-GHz/150-ns versatile pulsed measurement system for microwave transistor isothermal characterization

J.-P. Teyssier, P. Bouysse, Z. Ouarch, D. Barataud, T. Peyretaillade and R. Quere. "40-GHz/150-ns versatile pulsed measurement system for microwave transistor isothermal characterization." 1998 Transactions on Microwave Theory and Techniques 46.12 (Dec. 1998, Part I [T-MTT]): 2043-2052.

A versatile pulsed I(V) and 40-GHz RF measurement system is described with all the know-how and methods to perform efficient, safe, and reliable nonlinear transistor measurements. Capability of discrimination between thermal and trapping effects with a pulse setup is demonstrated. Capture and emission constant times of trapping effects are measured. A method to electrically measure the thermal resistance and capacitance of transistors with a pulse setup is proposed.

❑ Return to main document.